

**Search Notes**

Application/Control No.

10/692,160

Examiner

Hanh V. Tran

Applicant(s)/Patent under  
Reexamination

DEISS ET AL.

Art Unit

3637

**SEARCHED**

Class	Subclass	Date	Examiner
312	334.4 311	2/2/2006	HVT
	350 351		
134	137 58D		
	200 201	2/2/2006	
211	41.8 41.9	2/4/2006	
	175 181.1		
211	207 208	2/4/2006	HVT
All	Above	9/17/2006	HVT
	Updated		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East text search using various key words	2/2/2006	HVT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner